

ESD System Level, Factory/Materials, EDA Tools, and Failure Case Studies Sessions On-Demand from 2016 EOS/ESD Symposium



Experience the latest technical research as presented at the 2016 EOS/ESD Symposium

- Select Symposium paper presentations are being recorded for delivery online: on-demand after the 2016 EOS/ESD Symposium.
- Sessions listed to the right are included in this offer.
- Review as many sessions as you like, as often as you like!
- The 2016 proceedings will be included with your Symposium on Demand Purchase.

**\$195 per individual / \$50 Symposium Attendee or
University Professional/Student**

For more information visit:

www.esda.org/events/eosesd-symposia/symposia

**For abstracts of technical papers presented at the 2016 EOS/ESD Symposium please visit:
www.esda.org/events/eosesd-symposia/symposia/symposium-technical-sessions-2/**

Factory Control

- 2B.1 Electrostatic Shock Risks in Assembly of Large Wind Turbine Blades
- 2B.2 Product Qualification & Degradation of Steel Toe ESD Safety Footwear
- 2B.3 Charge Relaxation of Slowly Dissipative Polymers
- 4B.1 A Proposal of ESD Control Method with Considering Semiconductor Device Charged Voltage
- Rcj Invited Paper
- 4B.2 Reducing EOS Current in Hot Bar Process in Manufacturing of Fiber Optics Components
- 4B.3 Influence of Machine Configuration on EOS Damage during Wafer Cleaning Process

System Level ESD Design

- 3B.1 Measurement of Discharging Currents through an IC due to the Charged Board Event Using a Shielded Rogowski Coil
- 3B.2 Case Study of DPI Robustness of a MOS-SCR Structure for Automotive Applications
- 3B.3 HMM Single Site Testing: Can We Reproduce Component Failure Level with the HMM Document?

EDA Tools

- 5B.1 Empirical ESD Simulation Flow for ESD Protection Circuits Based on Snapback Devices
- 5B.2 An Automated Tool for Chip-Scale ESD Network Exploration and Verification
- 5B.3 EDA Approaches in Identifying Latch-up Risks
- 5B.4 Spice Modeling Flow for ESD Simulation of CMOS ICs

Failure Case Studies

- 6B.1 PMOS Arrays Self-Protection Capability Limitation
- 6B.2 Charged Cable/System ESD Event
- 6B.3 Gun Tests of a USB3 Host Controller Board

Setting the Global Standards for Static Control!

EOS/ESD Association, Inc. 7900 Turin Rd., Bldg. 3 Rome, NY 13440-2069, USA
PH +1-315-339-6937 • Email: info@esda.org • www.esda.org



ESD System Level, Factory/Materials, EDA Tools, and Failure Case Studies Sessions On-Demand from 2016 EOS/ESD Symposium

First Name: _____ Last Name: _____

Company Name: _____

Street: _____ City: _____

State/Province: _____ Country _____ Zip/Postal Code: _____

Address is (please circle the one that applies) Home or Company

Phone: _____ Fax: _____ E-mail: _____

Please list an email for each individual registering:

Email: _____

Email: _____

Email: _____

Email: _____

Email: _____

Email: _____

Email: _____

Email: _____

Technical Session Recording

Number of individuals:

_____ x \$195 = _____

Number of students or 2015 Symposium attendees:

_____ x \$50 = _____

Processing fee \$20

Total: _____

Credit card type: Visa® Mastercard® American Express® Discover®

Credit card number: _____ Security code: _____

Name on card: _____ Expiration date: _____

Card Holder Billing Address: _____

Card Holder Phone: _____

Setting the Global Standards for Static Control!

EOS/ESD Association, Inc. 7900 Turin Rd., Bldg. 3 Rome, NY 13440-2069, USA
PH +1-315-339-6937 • Email: info@esda.org • www.esda.org

